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Index

Volume 40, Nos. 1–4, 2008

ARTICLES

All articles are listed alphabetically by author and numbered sequentially. These sequential article numbers are used to identify the articles in the Key Words list, which begins on page 481.

1. Almini, A. A.; Kulahci, M.; and Montgomery, D., *Follow-Up designs to Resolve Confounding in Split-Plot Experiments* . . . . . April, 154–166
2. Anbari, F. T. and Lucas, J. M., *Designing and Running Super-Efficient Experiments: Optimum Blocking With One Hard-to-Change Factor* . . . . . January, 31–45
3. Apley, D. W. and Lee, H. C., *Robustness Comparison of Exponentially Weighted Moving-Average Charts on Autocorrelated Data and on Residuals* . . . . . October, 428–447
4. Bisgaard, S. and Huang, X., *Visualizing Principal Components Analysis for Multivariate Process Data* . . . . . July, 299–309
5. Bourke, P. D., *Performance Comparisons for the Synthetic Control Chart for Detecting Increases in Fraction Nonconforming* . . . . . October, 461–475
6. Braun, W. J. and Park, D., *Estimation of σ for Individuals Charts* . . . . . July, 332–344
7. Chang, T.-C., *Simultaneous Monitoring of Bias, Liniarity, and Precision of Multiple Measurement Gauges* . . . . . July, 268–281
8. Colosimo, B. M.; Pacella, M.; and Semeraro, Q., *Statistical Process Control of Geometric Specifications:On the Monitoring of Roundness Profiles* . . . . . January, 1–18
9. Danila, O.; Steiner, S. H.; and MacKay, R. J., *Assessing a Binary Measurement System* . . . . . July, 310–318
10. Edwards, D. J. and Mee, R. W., *Empirically Determined p-Values for Lenth t-Statistics* . . . . . October, 368–380
11. Engel, J., *Factorial Effects, Random Blocks, and Longitudinal Data: Two Simple Analysis Methods* . . . . . January, 97–108
12. Frey, D. D. and Li, X., *Using Hierarchhical Probability Models to Evaluate Robust Parameter Design Methods* . . . . . January, 59–77
13. González, I. and Sánchez, I., *Principal Alarms in Multivariate Statistical Process Control* . . . . . January, 19–30
14. Hao, S.; Zhou, S.; and Ding, Y., *Multivariate Process Variability Monitoring Through Projection* . . . . . April, 214–226
15. Jeng, S.-L.; Joseph, V. R.; and Wu, C. F. J., *Modeling and Analysis Strategies for Failure Amplification Method* . . . . . April, 128–139
16. Jensen, W. A.; Birch, J. B.; and Woodall, W. H., *Monitoring Correlation Within Linear Profiles Using Mixed Models* . . . . . April, 167–183
17. Jiang, W. and Tsui, K.-L., *A Weighted CUSUM Chart for Detecting Patterned Mean Shifts* . . . . . April, 194–213
18. Joseph, V. R. and Delaney, J. D., *Analysis of Optimization Experiments* . . . . . July, 282–298
19. Li, J.; Jin, J.; and Shi, J., *Causation-Based T^2 Decomposition for Multivariate Process Monitoring and Diagnosis* . . . . . January, 46–58
20. Lupinacci, P. J. and Pigeon, J. G., *A Class of Partially replicated Two Level Fractional Factorial Designs* . . . . . April, 184–193
21. Majeske, K. D., *Approval Criteria for Multivariate Measurement Systems* . . . . . April, 140–153

22. McLeod, R. G. and Brewster, J. F., *Optimal Foldover Plans for Two-Level Fractional Factorial Split-Plot Designs* . . . . . April, 227–240
23. Mee, R. W. and Xiao, J., *Optimal Foldovers and Semifolding for Minimum Aberration Even Fractional Factorial Designs* . . . . . October, 448–460
24. Monroe, E. and Pan, R., *Experimental Design Considerations for Accelerated Life Tests With Nonlinear Constraints and Censoring* . . . . . October, 355–367
25. Piepel, G. F.; Cooley, S. K.; and Paul, M. R., *Upper Tolerance Intervals Adjusted for Multiple Nuisance Uncertainties* . . . . . July, 245–258
26. Pulcini, G., *Repairable System Analysis for Bounded Intensity Functions and Various Operating Conditions* . . . . . January, 78–98
27. Reese, C. S.; Deininger, P.; Hamada, M. S.; and Krabill, R., *Exploring the Statistical Advantages of Nondestructive Evaluation Over Destructive Testing* . . . . . July, 259–267
28. Reynolds, Jr., M. R. and Stoumbos, Z. G., *Combinations of Multivariate Shewhart and MEWMA Control Charts for Monitoring the Mean Vector and Covariance Matrix* October, 381–393
29. Shu, L. and Jiang, W., *A New EWMA Chart for Monitoring Process Dispersion* . . July, 319–331
30. Vining, G. G. and Kowalski, S. M., *Exact Inference for Response Surface Designs Within a Split-Plot Structure* . . . . . October, 394–406
31. Wang, K. and Tsung, F., *An Adaptive T^2 Chart for Monitoring Dynamic Systems* January, 109–123
32. Zou, C. and Tsung, F., *Directional MEWMA Schemes for Multistage Process Monitoring and Diagnosis* . . . . . October, 407–427

DEPARTMENTS

Book Reviews

DOE Simplified: Practical Tools for Effective Experimentation, Second Edition by M. Anderson and P. Whitcomb . . . . . W. A. Jensen January, 124–125
Generalizesd Linear Models and Extensions, Second Edition by J. W. Hardin and J. M. Hilbe . . . . . C. M. Borror April, 241–242
Introduction to Time Series Analysis and Forecasting by D. Montgomery, C. Jennings, and M. Kulahci . . . . . T. L. Utlaut October, 476–478
Life Cycle reliability Engineering by G. Yang . . . . . W. Meeker July, 345–348
Linear Mixed Models, A Practical Guide Using Statistical Software by B. T. West, K. B. Welch, and A. T. Gałecki with contributions from by B. W. Gillespie . . . . . D. Jearkpaporn April, 243–244
Nonparametric Statistics with Applications to Science and Engineering by P. H. Kvam and B. Vidakovic . . . . . T. L. Utlaut July, 352–353
Process Optimization: A Statistical Approach by E. del Castillo . . . . . D. Neubauer July, 348–351
Statistics for Engineering and Scientists, Second Edition by W. Navidi . . . . . J. Egenolf April, 242–243
Testing 1-2-3: Experimental Design with Applications in Marketing and Service Operations by Johannes Ledolter and Arthur J. Swersey . . . . . Jim Rutledge October, 476
Visual Statistics: Seeing Data with Dynamic Interactive Graphics by F. Young, P. Malero-Mora, and M. Friendly . . . . . C. M. Mastrangelo January, 125–126

Book Reviewers

Borror, C. M. . . . . April, 241–242
Egenolf, J. . . . . April, 242–243
Jearkpaporn, D. . . . . April, 243–244
Jensen, W. A. . . . . January, 124–125
Mastrangelo, C. M. . . . . January, 125–126
Meeker, W. . . . . July, 345–348
Neubauer, D. . . . . July, 348–351
Rutledge, J. . . . . October, 476
Utlaut, T. L. . . . . July, 352–353
Utlaut, T. L. . . . . October, 476–478

MISCELLANEOUS

In Memoriam: Zachary G. Stoumbos . . . . . April, 127

KEY WORDS

The numbers listed by the key words are the identification numbers assigned to the articles as listed on the previous pages.

Accelerated Tests; 26
Adaptive Chart; 31
Alias; 1
Alias-length Pattern; 23
Analytical Uncertainty; 25
Attributes-Data Control Chart; 5
Automatic Process Control; 17
Autoregressive Moving-Average Model; 3
Average Run Length; 7, 13, 29, 32
Average Time to Signal; 28
Bayesian; 27
Bayesian Network; 19
Block Size; 2
Blocking; 22
Blocked designs; 11
Causal Model; 19
Center-Point Replication; 10
Central Composite Designs; 30
Change-Point Detection; 17
Chi-Squared Distribution; 7
Clear Effects; 22
Cointegration; 4
Combined Array; 12
Combined Design; 22
Conforming Run-Length; 5
Continuous and Discrete Measurements; 27
Control Chart; 3, 8, 13, 14
Cost Function; 2
Data Mining; 4
Derived Variables Analysis; 11
Design Augmentation; 23
Design of Experiments; 15, 30
Directionally Variant Chart; 31
D-Optimality; 24
Dynamic Linear Models; 6
Eblups; 16
Econometrics; 4
Effect Sparsity; 10
Empirical Bayes Method; 18
Expensive-to-Change Factor; 2
Experimental Design; 24
Exponentially Weighted Moving Average; 17, 31
EWMA Chart; 32
F Distribution; 7
Foldover Design; 1
Gamma Distribution; 29
Gauge R&R; 9
Gauge Study; 21
G-Efficiency; 2
G_2-Aberration; 20
Generalized Likelihood Ratio Test; 32
Generalized Linear Models; 15
Generalized Resolution; 20
Generalized Variance; 14
Geometric CUSUM
Geometric Tolerance; 8
Go/No Go Testing; 9
Hadamard Matrix; 20
Hotelling's T^2; 13
Hotelling's T^2 Statistic; 31
Inspection Errors; 9
Joint Probability Distribution; 7
Loess; 6
Longitudinal Data; 11
MANOVA; 21
Markov Chain; 29
Measurement-Systems Analysis; 21
Metropolis-Hastings Algorithm; 27
MEWMA; 13
MEWMA Control Chart; 28
Minimal Design; 23
Minimum Aberration; 1, 22
Misclassification Rates; 9
Missing Data; 10, 16
Mixed Model; 11, 16
Model Error; 3
Model Selection; 15
Model Uncertainty; 25
Monte Carlo Simulation; 25
Moving Ranges; 6
Multivariate Analysis; 4
Multivariate Capability; 21
Multivariate Control Chart; 8, 32
Multivariate Process; 13
Multivariate Process Variability; 14
Multivariate Statistical Process Control; 16

Noncentral Chi-Squared Distribution; 7
Noncentral t-Distribution; 25
Nonhomogeneous Poisson Process; 26
Pass-Fail Inspection; 9
Phase I; 16
Practical Significance Level; 18
Prediction Variance; 2
Principal Component; 13
Process Capability; 15
Process Dynamics; 31
Product Array; 12
Profile Monitoring; 8
Pure Error; 10
Recursive Residual; 32
Reduced Defining Relation; 1
Regression; 8
Regression Adjustment of Variables; 28
Regression Model; 26
Reliability; 24, 26
Resolution III Design; 1
Resolution IV; 23
Resolution IV Design; 1
Response Modeling; 12
Response Surface Methodology; 30
Restricted Randomization; 22
Robust Parameter Design; 15
Robustness; 3
Sampling Uncertainty; 25
Satterthwaite's Method; 25
Saturated Model; 10
Shewhart Chart; 28
Shrinkage Estimation; 18
Signal-to-Noise Ratio; 12, 21
Smoothing; 6
Solder Joint Reliability; 24
Spatial Statistics; 8
SPC; 8, 19
Split-Plot Design; 1
Split-Plot Experiment; 30
Squared Deviations from Target; 28
Statistical Graphics; 4
Statistical Modeling; 11
Statistical Process Control; 3, 4, 5, 7, 14, 17, 28, 29
Steady-State Average Time to Signal; 28
Surveillance; 28
T^2 Statistic; 16
Temperature Cycle; 24
Transient Shift; 28
Uniformity; 20
Variable Selection; 18
Variance; 29